

EAST Search History

| Ref # | Hits | Search Query | DBs | Default Operator | Plurals | Time Stamp |
|-------|-------|---|---|------------------|---------|------------------|
| L1 | 8 | ((test\$ near memory) (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/25 16:26 |
| S1 | 11768 | (test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and (conver\$5 near circuit) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/17 23:48 |
| S2 | 55309 | test\$3 near memory | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 14:02 |
| S3 | 36 | test\$3 with memory | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 14:02 |
| S4 | 8 | (test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and (conver\$5 near circuit) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 14:18 |
| S5 | 0 | (test\$3 with memory) and (test near (pattern patterns vector vectors data signals) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and (conver\$5 near circuit) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2007/01/17 23:48 |
| | | ((BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/738.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 17:10 |

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| S6 | 1 | ((BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit)) and 714/733.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 17:10 |
| S7 | 2 | (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH) near circuit) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 17:10 |
| S8 | 36 | (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 17:10 |
| S9 | 52 | ((test\$3 near memory) (BIST "built-in self-test" ("in circuit" near test\$3) LBIST MBIST)) and (test near (pattern patterns vector vectors data signals signal) near (generat\$3)) and ((physical and logical) near (address location cell cells addresses locations)) and ((conver\$5 RAM ROM EPROM EEPROM FLASH)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/03/29 17:12 |
| S10 | 10 | ("4754215", "4862460", "5214654", "5314492", "5739778").pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/04/21 18:01 |
| S11 | 2 | "6065145".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/11/17 16:52 |
| S12 | 1256 | clock near align\$5 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2004/11/17 16:52 |

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|-----|------|---|---|----|-----|------------------|
| S13 | 1370 | clock near align\$5 | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/11/17 16:52 |
| S14 | 9 | (clock near align\$5) and (delay near test\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2004/11/17 16:53 |
| S15 | 1987 | yamada.in. and "integrated circuit" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2005/12/26 20:17 |
| S16 | 2245 | yamada.in. and "integrated circuit" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/12/26 20:18 |
| S17 | 6 | yamada.in. and "integrated circuit" and advantest.as. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/12/26 20:18 |
| S18 | 0 | (osamu and yamada).in. and "integrated circuit" and advantest.as. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/12/26 20:18 |
| S19 | 38 | (osamu and yamada).in. and "integrated circuit" | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/12/26 20:18 |
| S20 | 0 | (osamu and yamada).in. and "integrated circuit" and (memory near test\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/12/26 20:19 |
| S21 | 129 | 714/738.CCLS. and "integrated circuit" and (memory near test\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2005/12/26 20:19 |
| S22 | 871 | 714/733.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 20:31 |

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| S23 | 3270 | (714/733.ccls. 714/734.ccls. (built-in near test\$3)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 20:32 |
| S24 | 0 | (714/733.ccls. 714/734.ccls. (built-in near test\$3)) and (neighborhood near sensitive near test\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 20:32 |
| S25 | 2 | (714/733.ccls. 714/734.ccls. (built-in near test\$3)) and (neighborhood near test\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 20:33 |
| S26 | 24 | (714/733.ccls. 714/734.ccls. (built-in near test\$3)) and (sensitive near test\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 20:46 |
| S27 | 4 | (714/733.ccls. 714/734.ccls. (built-in near test\$3)) and ((physical and logical) with (conver\$5)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/23 20:46 |
| S28 | 3 | "6815977".pn. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/24 15:03 |
| S29 | 29 | (master and slave) with (scan adj cell) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/24 15:03 |
| S30 | 1187 | (master and slave) with (cell) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/24 15:03 |
| S31 | 21 | ((master and slave) with (scan adj cell)) and (scan near test\$3) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/24 15:04 |
| S32 | 1914 | (convert\$5 with physical with logical with address) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/24 15:58 |

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| S33 | 2 | (convert\$5 with physical with logical with address) and (714/733.ccls. 714/734.ccls. (built-in near test\$3)) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/24 15:59 |
| S34 | 871 | 714/733.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | OFF | 2006/05/24 17:23 |
| S35 | 147 | kato.in. and (crc) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/25 16:27 |
| S36 | 48 | kato.in. and (crc and packet) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/25 16:27 |
| S37 | 0 | kato.in. and (crc and packet).ab. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/25 16:27 |
| S38 | 48 | kato.in. and (crc and packet) | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/25 16:27 |
| S39 | 5 | kato.in. and (crc and packet) and BCH | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/25 16:28 |
| S40 | 1450 | 714/758.ccls. | US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB | OR | ON | 2006/05/25 16:28 |